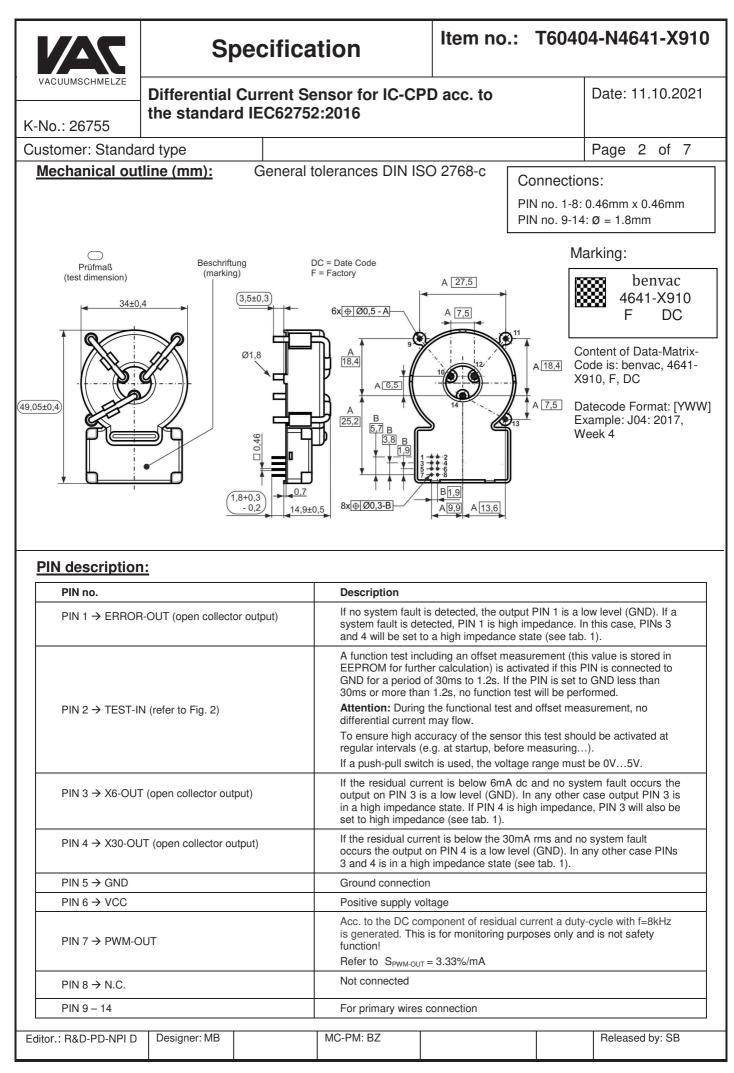
	S	pecifica	tion	Item no	Item no.: T60404-N4641-				
K-No.: 26755	Differential the standar		nsor for IC-CF 2:2016	PD acc. to		Date: 11	.10.2021		
Customer: Standa	ard type					Page 1	of 7		
	••				A	Ū	0		
 Description Fluxgate current s toroidal core PCB mounting 	ensor with	aracteristics Excellent accu AEC-Q qualifi Switching ope Compact desi		Mainly ι	cations used for obile ap IC-CPD acc. T				
Patents: EP257112		CN103001175 //	EP2813856		<u> </u>				
Electrical data				min.	typ.	max.	Unit		
I _P	Primary nomin		· · /		_	20	A		
	Rated residual				6		mA DC		
IΔN2	Rated residual		rent 2		30	-	mA rms		
$\Delta N1$, tolerance	Trip tolerance			4	5	6	mA DC		
$\Delta N2$, tolerance	Trip tolerance			20		30(1) / 60(2)	mA rms		
Spwm-out	Scaling factor (for monitorin	ng purpose or	nly!)		3.33		%/mA		
$I_{\Delta RI,1/2}$ (Fig.1)	Recovery curre (absolute value		N1/IAN2		2.5 / 10		mA		
	(/			(1) f = D	C to 1kHz (2) f = -	1kHz to 2kHz		
<u> Accuracy – Dyr</u>	namic perform	nance data							
I _{∆N,max}	Measuring ra	nge (peak)		-300		+300	mA		
Х		\bigcirc I _{ΔN} , $\Theta_A = 25^{\circ}$	C)		< 0.2		mA		
tr (Fig.3)	Response tim				According	to IEC62752:201			
f _{BW} (Fig.4)	Frequency ra	nge		DC		2	kHz		
General data									
ЭA	Ambient oper	ration tempera	ture	-40		85	°C		
9 Storage	Ambient stora	age temperatu	re ⁽⁴⁾	-40		85	°C		
m	Mass				26		g		
Vcc	Supply voltag	je		4.8	5	5.2	V		
lcc	Supply currer	nt		38		45	mA rms		
Sclear, pp		rimary to prima	• /		>1.94		mm		
Screep, pp		imary to prima	• /		>2.50		mm		
Sclear, ps		rimary to seco	• /		>3.87		mm		
Screep, ps		imary to secor	• /		>5.00		mm		
FIT		9 / SN 29500(6	š)		1529		fit		
Reinforced insulati ⁽⁶⁾ The results are vali	101; storage tempera tured and tested in a on, Insulation materia d under following cor	ms) is considered. ture inside cardboa ccordance with IEC al group 1, Pollution nditions: 55°C mear	rd packaging 60664-1:2007. The insul n degree 2, altitude ≤ 400 n component ambient te substances, according f	00m and overvolta mperature by con	ige category II. tinuous operat	ion (8760h per yea			
applications. The fault current, PIN current fault, PIN Error conditions	ensitive to AC ar Sensor detects I 3 will change it Is 3 and 4 will ch (e.g. an internal	nd DC current a AC and DC fa 's state from a nange state fro	and can be used fo ault currents accor low level (GND) to m a low level (GN naled on PIN 1 (EF	ding to IEC62 o high impeda D) to a high in	2752:2016. ance level.	In the event of an			
Datum Name Index									
11.10.2021BZ8402.07.19BZ84		n sheet 1. CN-21- t test 3.4a deleted							
. .	-	1 1001 0.44 0010100				<u> </u>			
Editor.: R&D-PD-NPI D	Designer: MB		MC-PM: BZ			Released	by: SB		

Copying of this document, disclosing it to third parties or using the contents there for any purposes without express written authorization by use illegally forbidden. Any offenders are liable to pay all relevant damages



Copying of this document, disclosing it to third parties or using the contents there for any purposes without express written authorization by use illegally forbidden. Any offenders are liable to pay all relevant damages

	Specification			Item no.:	Г60404-N4	404-N4641-X910			
	Differential the standar		ensor for IC-CI 2:2016	PD acc. to	Date:	Date: 11.10.2021			
K-No.: 26755						0 (7		
Customer: Standa					Page	3 of	/		
<u>Typical applica</u>	tion diagram:	PIN 9 PIN 11 PIN 13		PIN 10 PIN 12 PIN 14	LL				
to driver circuit , control electronic		PIN 3 PIN 4 PIN 4 PIN 7 PIN 7 PIN 7 PIN 7 PIN 7 PIN 7 PIN 7	^{Min} control electronic _{in} e.g. charger	PIN 2 PIN 2 PIN 6 Vcc Inductance GND PIN 5 PIN 8 n.c.					
Absolute maxir	num ratings(7)	<u>:</u>							
VCE	Collecto	r-Emitter volta	ge (PINs 1, 3 and	4)		40	V		
lc Vcc		r current (PINs	,	on) -0.3		50 7	mA V		
VCC U _{MAX}			ge (without function e of primary cond			250	V		
VTEST-IN, Iow		I Input Voltage		0		0.6	V		
VTEST-IN, high		I Input Voltage		2.5		5	V		
⁽⁷⁾ Stresses above t Exposure to these Functional operations specified is not sup	conditions for exte on of the device at	ended periods ma	t damage. ay degrade device re er conditions beyond MC-PM: BZ	liability. d those	Relea	sed by: Si	В		

	S	oecifica	tion	Item no.:	T60404	4-N464	1-X910	
K-No.: 26755	Differential the standar		Date: 11.10.2021					
Customer: Standa	ard type					Page 4 of 7		
Final Tests: (Me		temperature ba	lance of the sample	s at room temperat		•		
<u> </u>			·····		-	lax.	Unit	
Vcc	Sup	ply voltage			4.9	5.1	V	
lcc	Sup	oly current			38.0	45.0	mA	
TEST-IN (SC)		T-IN voltage			2.8	3.3	V	
X6-OUT (normal)		OUT voltage			0	0.6	V	
X30-OUT (normal	,	OUT voltage			0	0.6	V	
ERROR-OUT (no	,	OR-OUT voltag			0	0.6	V	
X6-OUT (activate	•	-	vated @5V, 1kΩ (pul		4.9	5.1	V	
X30-OUT (activat		U	tivated @5V, 1kΩ (pu	17	4.9	5.1	V	
ERROR-OUT (ac	/		e activated @5V, 1k	Ω (pull-up)*	4.9	5.1	V	
TC1	· · · ·	current 1 – X6			4.1	5.4	mA	
TC2		current 2 – X6			-5.4	-4.1	mA	
TC3		current 3 – X30	-		20	30	mA	
PWM-OUT (frequ		A-OUT frequence	•		7.8	8.2	kHz	
PWM-OUT (duty-	• ,	Λ-OUT duty-cyc		4.00	18	22	%	
LV1			time - X6-OUT@6		0	700	ms	
LV2			time - X6-OUT@30	0	500	ms		
LV3	50H:		time - X30-OUT@3	SUITA,	0	300	ms	
LV4	LV4 Limit values of break time - X30- 0 OUT@150mA,50Hz						ms	
<u>Product Tests:</u>	Ace	c. to VAC shee lowing tests di	et M3238 ffer from M3238:		ł	bassed		
	Du	a: Damp heat, ration: 1000 h	-			1.5		
PD	UP		N60270,M3024 artial discharge vo to table 24	ltage		1.5	kV rms	
ESD	U= Ace	c. to Human B	00Ω, C=100pF ody Model JESD2			±2.0	kV	
	ele 801 wit	ctromagnetic f MHz – 1GHz 8	adiated, radio-frec ield immunity) 20\ 0%AM 1kHz, reco ductance of >220µ ut.	V/m ommend	ра	ssed		
EMC	CIS	SPR 14-1 (Imn turbances), red uctance of >22	·	passed				
	ind	C61000-6-4 (E ustrial environ turbances)	do en	Should be done in end application				
A (f), Φ(f)		plitude and ph quency 1% of	ase response ove	er	ра	ssed		
Impulse test	Мо		function during th	e current	ра	ssed		
Editor.: R&D-PD-NPI D	·		MC-PM: BZ			Released b	w: SB	
∟αιίοι καυ-Υυ-ΝΥΙ υ						i leieaseu L	y. 00	

Copying of this document, disclosing it to third parties or using the contents there for any purposes without express written authorization by use illegally forbidden. Any offenders are liable to pay all relevant damages

VACUUMSCHMELZE K-No.: 26755		Specification			Item no.: T60404-N4641-X910				
			ifferential Current Sensor for IC-CPD acc. to ne standard IEC62752:2016					1.10.2021	
Customer: Standard type							Page	5 of 7	
Requalifica	ation	Tests: (repli	cated every	vyear, Precondition acc. to M3238)					
Ûw, prim-sec	M30	64	PIN 1-8	test (1.2µs/50µs waveform) vs. PIN 9-14 → polarity +, 5 pulse → pola	arity -		5.5	kV rms	
Ûw, prim-prim	M30	64	Impulse PIN 9 vs	test (1.2µs/50µs waveform) s. PIN 11, PIN 11 vs. PIN 13, → polarity +, 5 pulse → pola	PIN 13 vs. PIN	9	4.0	kV rms	
Ud	M30	14		tage, 60s vs. PIN 9-14			1.5	kV rms	
Ud, prim-prim	M30	14		tage between primary condu s. PIN 11,PIN 11 vs. PIN 13,)	1.5	kV rms	
U _{PDE}	M30	24	Partial d	lischarge voltage (extinction) vs. PIN 9-14			1.2	kV rms	
U _{PD} x 1.875	M30	24		lischarge voltage (extinction) vs. PIN 9-14 ble 24			1.5	kV rms	
* IEC 61800-5-1:2007									

Other instructions:

-Temperature of the primary conductor should not exceed 105°C.

-Vcc during Test-IN function test must be at least 4.8V

-Fall- and rise-time of Vcc 2...50µs/V

Figures:

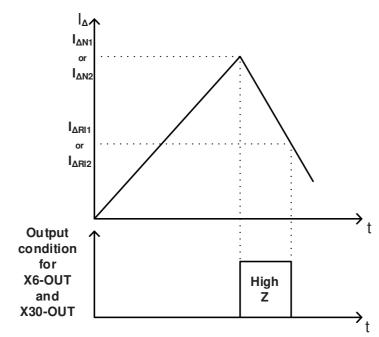
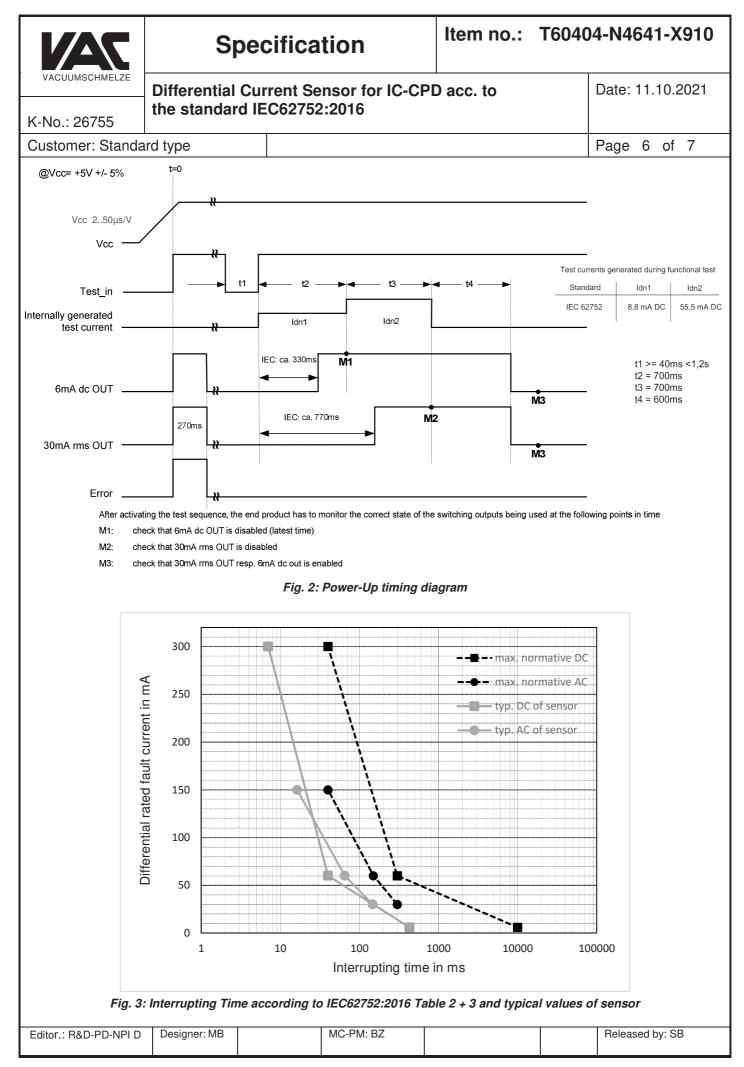


Fig. 1: Meaning of switching recovery level

If the trip-level $I_{\Delta N1}/I_{\Delta N2}$ is accomplished the outputs X6-OUT/X30-OUT will change their state from low-level (GND) to high impedance. Depending on the existence of the residual current I_{Δ} , the outputs X6-OUT/X30-OUT will remain in this state until I_{Δ} falls below the threshold $I_{\Delta R11}/I_{\Delta R12}$.

Editor.: R&D-PD-NPI D	Designer: MB	MC-PM: BZ		Released by: SB



Copying of this document, disclosing it to third parties or using the contents there for any purposes without express written authorization by use illegally forbidden. Any offenders are liable to pay all relevant damages

		7	Sp	oecifica	Iten	Item no.: T60404-N4641-X910						
VACUUMSCHMELZEDifferential Current Sensor for IC-CPD acc. tK-No.: 26755the standard IEC62752:2016							. to	Date: 11.10.2021				
Cus	tomer: St	andar	rd type							Page 7 of 7		
response value / mA	1000										· * * * * * * * * * * * * * * * * * * *	
	1			10	Free	quency / H	100	 limits acc.	to IEC6275		00	,
				Fig. 4: Re	sponse	value over	frequen	cy				
			X6-OUT	X30-OI	UT	ERROR	-OUT	St	ate			
			GND	GND)	GN	D	Normal	condition	1		
			High impedance	e GND)	GN	D	I _{∆N1} ≥	6mA _{DC}			
			High impedance	e High impe	dance	GN	D	I _{∆N2} ≥ 3	30mA _{rms}			
			High impedance			High imp			stem faul ⁻	t		
			All other cond conditions oc									
		L		cur, the sense		IIIKIIOWII S		uescribes	dii Eli Ol.			
				Table	1: Poss	ible output	states					
Edito	r.: R&D-PD-	NPI D	Designer: MB		MC-PM	BZ				Rele	ased by: SE	3